



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

<p>In re application of:</p> <p>Young et al.</p> <p>Serial No.: 10/614,311</p> <p>Filed: July 7, 2003</p> <p>Title: AVANCED BI-DIRECTIONAL LINEAR POLISHING SYSTEM AND METHOD</p>	<p>Group Art Unit: Not yet assigned</p> <p>Examiner: Not yet assigned</p> <p>Docket: NT-251C1-US</p>
---	--

INFORMATION DISCLOSURE STATEMENT

US PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	
DBT		669,923	Mar., 1901	Grauert	In Serial No. 09/684,059
		3,888,050	June, 1975	Elm	In Serial No. 09/684,059
		4,412,400	Nov., 1983	Hammond	In Serial No. 09/684,059
		4,802,309	Feb., 1989	Heynacher	In Serial No. 09/684,059
		5,245,796	Sep., 1993	Miller et al.	In Serial No. 09/684,059
		5,335,453	Aug., 1994	Baldy et al.	In Serial No. 09/684,059
		5,377,452	Jan., 1995	Yamaguchi	In Serial No. 09/684,059
		5,377,453	Jan., 1995	Perneckzy	In Serial No. 09/684,059
		5,429,733	July, 1995	Ishida	In Serial No. 09/684,059
		5,489,235	Feb., 1996	Gagliardi et al.	In Serial No. 09/684,059
		5,558,568	Sep., 1996	Talieh et al.	In Serial No. 09/684,059
		5,593,344	Jan., 1997	Weldon et al.	In Serial No. 09/684,059
		5,650,039	July, 1997	Talieh	In Serial No. 09/684,059
		5,679,212	Oct., 1997	Kato et al.	In Serial No. 09/684,059
		5,692,947	Dec., 1997	Talieh et al.	In Serial No. 09/684,059
		5,707,409	Jan., 1998	Martin et al.	In Serial No. 09/684,059
		5,759,918	June, 1998	Hoshizaki et al.	In Serial No. 09/684,059
		5,762,751	June, 1998	Bleck et al.	In Serial No. 09/201,928
		5,770,521	June, 1998	Pollock	In Serial No. 09/201,928
		5,807,165	Sep., 1998	Uzoh et al.	In Serial No. 09/201,928
		5,810,964	Sep., 1998	Shiraishi	In Serial No. 09/684,059
		5,851,136	Dec., 1998	Lee	In Serial No. 09/684,059
		5,893,755	April, 1999	Nakayoshi	In Serial No. 09/684,059
		5,899,798	May, 1999	Trojan et al.	In Serial No. 09/684,059
		5,899,801	May, 1999	Trolles et al.	In Serial No. 09/684,059
		5,908,530	June, 1999	Hoshizak et al.	In Serial No. 09/684,059
		5,913,716	June, 1999	Mucci et al.	In Serial No. 09/684,059
		5,951,368	Sep., 1999	Watanabe et al.	In Serial No. 09/684,059
		5,951,377	Sep., 1999	Vaughn et al.	In Serial No. 09/684,059
		5,961,372	Oct., 1999	Shendon	In Serial No. 09/684,059
		5,975,988	Nov., 1999	Christianson	In Serial No. 09/684,059

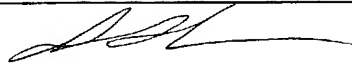
DBT		6,017,831	Jan., 2000	Beardsley et al.	In Serial No. 09/684,059
		6,068,542	May, 2000	Hosokai	In Serial No. 10/126,469
		6,110,025	Aug., 2000	Williams et al.	In Serial No. 10/126,469
		6,113,479	Sep., 2000	Sinclair et al.	In Serial No. 10/126,469
		6,129,540	Oct., 2000	Hoopman et al.	In Serial No. 10/126,469
		6,135,859	Oct., 2000	Tietz	In Serial No. 10/126,469
		6,136,715	Oct., 2000	Shendon et al.	In Serial No. 10/126,469
		6,179,690	Jan., 2001	Talieh	In Serial No. 10/126,469
		6,179,709	Jan., 2001	Redeker et al.	In Serial No. 10/126,469
		6,207,572	Mar., 2001	Talieh	In Serial No. 09/684,059
		6,241,583	June, 2001	White	In Serial No. 10/126,469
		6,302,767	Oct., 2001	Tietz	In Serial No. 10/126,469
		6,312,319	Nov., 2001	Donohue et al.	In Serial No. 10/126,469
		6,379,231	April, 2002	Birang et al.	In Serial No. 10/126,469
		6,413,873	July, 2002	Li et al.	In Serial No. 10/126,469
		6,419,559	July, 2002	Gurusamy et al.	In Serial No. 10/252,149
		6,428,394	Aug., 2002	Mooring et al.	In Serial No. 10/252,149
		6,439,978	Aug., 2002	Jones et al.	In Serial No. 10/252,149
		6,468,139	Oct., 2002	Talieh et al.	In Serial No. 10/252,149
		6,475,070	Nov., 2002	White	In Serial No. 10/252,149
DBT		6,500,056	Dec., 2002	Krusell et al.	In Serial No. 10/252,149

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	
DBT		DE 31 13 204	Oct., 1982	Lambelet	In Serial No. 09/684,059
		EP 0 517 594	Dec., 1992	Baldy	In Serial No. 09/684,059
		WO 97 20660	June, 1997	Shendon	In Serial No. 09/684,059
		WO 98/45090	Oct., 1998	Donhue et al.	In Serial No. 09/684,059
		WO 99/22908	May, 1999	Sommer	In Serial No. 09/684,059
		EP 0 941 806 A2	Sep., 1999	Jew et al.	In Serial No. 09/684,059
		WO 00/32356	June, 2000	Talieh	In Serial No. 09/684,059
		EP 1 025 955 A2	Aug., 2000	Somekh et al.	In Serial No. 09/684,059
DBT		WO 02/02272 A1	Jan., 2002	Owczarz et al.	In Serial No. 09/684,059

OTHER DOCUMENTS

Examiner Initials	Cite No.			Translation
DBT		J.M. Steigerwald, et al., "Pattern Geometry Effects in the Chemical-Mechanical Polishing of Inlaid Copper Structures", Oct. 1994, pp. 2842-2848.	In Serial No. 09/576,064	

Examiner Signature		Date Considered	5/29/04
--------------------	---	-----------------	---------